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- State-of-the-Art BiCMOS Design Significantly Reduces I<sub>CCZ</sub>
- 3-State True Outputs
- Back-to-Back Registers for Storage
- ESD Protection Exceeds 2000 V Per MIL-STD-883C, Method 3015
- Package Options Include Plastic Small-Outline Packages (DW), Ceramic Chip Carriers (FK) and Flatpacks (W), and Plastic and Ceramic 300-mil DIPs (JT, NT)

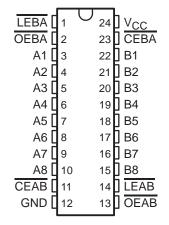
#### description

The 'BCT543 octal transceiver contains two sets of D-type latches for temporary storage of data flowing in either direction. Separate latch-enable (\overline{LEAB}\) or \overline{LEBA}\) and output-enable (\overline{OEAB}\) or \overline{OEBA}\) inputs are provided for each register to permit independent control in either direction of data flow.

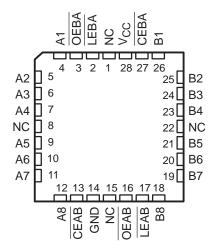
The A-to-B enable (\overline{CEAB}) input must be low in order to enter data from A or to output data from B. If \overline{CEAB} is low and \overline{LEAB} is low, the A-to-B latches are transparent; a subsequent low-to-high transition of \overline{LEAB} puts the A latches in the storage mode. With \overline{CEAB} and \overline{OEAB} both low, the 3-state B outputs are active and reflect the data present at the output of the A latches. Data flow from B to A is similar but requires using the \overline{CEBA}, \overline{LEBA}, and \overline{OEBA} inputs.

The SN54BCT543 is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to 125°C. The SN74BCT543 is characterized for operation from 0°C to 70°C.

SN54BCT543 . . . JT OR W PACKAGE SN74BCT543 . . . DW OR NT PACKAGE (TOP VIEW)



SN54BCT543 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

#### **FUNCTION TABLE**†

	INPL	OUTPUT		
CEAB	LEAB	OEAB	Α	В
Н	Х	Х	Χ	Z
Х	Χ	Н	X	Z
L	Н	L	Χ	в <sub>0</sub> ‡
L	L	L	L	L
L	L	L	Н	Н

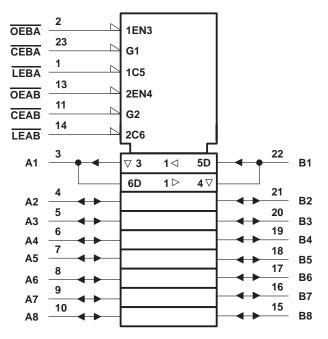
<sup>†</sup> A-to-B data flow is shown; B-to-A flow control is the same except that it uses CEBA, LEBA, and OEBA.



<sup>&</sup>lt;sup>‡</sup>Output level before the indicated steady-state input conditions were established.

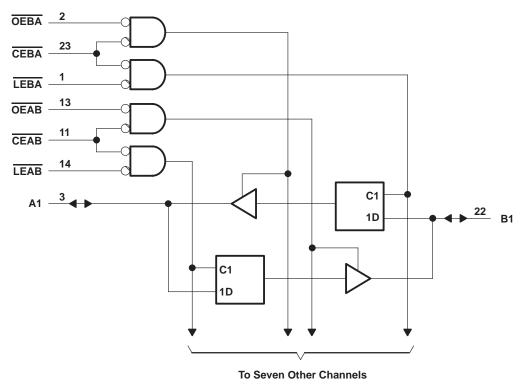
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## logic symbol†



<sup>&</sup>lt;sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

# logic diagram (positive logic)



Pin numbers shown are for the DW, JT, NT, and W packages.



## SN54BCT543, SN74BCT543 OCTAL REGISTERED TRANSCEIVERS WITH 3-STATE OUTPUTS

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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>		– 0.5 V to 7 V
Input voltage range: Control inputs (see	e Note 1)	– 0.5 V to 7 V
I/O ports (see Note	e 1)	– 0.5 V to 5.5 V
Voltage range applied to any output in t	he disabled or power-off state, VO	– 0.5 V to 7 V
Voltage range applied to any output in t	he high state, VO	– 0.5 V to V <sub>CC</sub>
Input clamp current, I <sub>IK</sub>		
Current into any output in the low state:	SN54BCT543	96 mA
	SN74BCT543	128 mA
Operating free-air temperature range:	SN54BCT543	– 55°C to 125°C
	SN74BCT543	0°C to 70°C
Storage temperature range		– 65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

### recommended operating conditions

		SN54BCT543			SN	UNIT		
		MIN NOM MAX		MIN	NOM	MAX	UNIT	
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
V <sub>IL</sub>	Low-level input voltage			0.8			0.8	V
ΙΙΚ	Input clamp current			-18			-18	mA
IOH	High-level output current			-12			-15	mA
loL	Low-level output current			48			64	mA
TA	Operating free-air temperature	-55		125	0		70	°C

## SN54BCT543, SN74BCT543 OCTAL REGISTERED TRANSCEIVERS WITH 3-STATE OUTPUTS

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# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS		SN	I54BCT5	43	SN74BCT543			UNIT
				MIN	TYP	MAX	MIN	TYP†	MAX	UNII
VIK		$V_{CC} = 4.5 \text{ V},$	I <sub>I</sub> = -18 mA			-1.2			-1.2	V
			$I_{OH} = -3 \text{ mA}$	2.4	3.3		2.4	3.3		
Vон		V <sub>CC</sub> = 4.5 V	$I_{OH} = -12 \text{ mA}$	2	3.2					V
			$I_{OH} = -15 \text{ mA}$				2	3.1		
Vai		V00 - 4 F V	I <sub>OL</sub> = 48 mA		0.38	0.55				V
VOL		V <sub>CC</sub> = 4.5 V	I <sub>OL</sub> = 64 mA					0.42	0.55	V
Ц		$V_{CC} = 5.5 V,$	V <sub>I</sub> = 5.5 V			0.4			0.4	mA
. +	A or B port	V <sub>CC</sub> = 5.5 V,	V <sub>1</sub> = 2.7 V			70			70	μΑ
I <sub>IH</sub> ‡	Control input		$V_{I} = 2.7 \text{ V}$			20			20	
. +	A or B port	V <sub>CC</sub> = 5.5 V,	V <sub>I</sub> = 0.5 V			-0.65			-0.65	mA
I <sub>IL</sub> ‡	Control input		V  = 0.5 V			-0.6			-0.6	IIIA
los§		$V_{CC} = 5.5 V,$	V <sub>O</sub> = 0	-100		-225	-100		-225	mA
ICCL	A or B port	V <sub>CC</sub> = 5.5 V			45	71		45	71	mA
Іссн	A or B port	V <sub>CC</sub> = 5.5 V			5	8		5	8	mA
ICCZ	A or B port	V <sub>CC</sub> = 5.5 V			9	15		9	15	mA
Ci	Control input	V <sub>CC</sub> = 5 V,	$V_{I} = 2.5 \text{ V or } 0.5 \text{ V}$		6			6		pF
C <sub>io</sub>	A or B port	V <sub>CC</sub> = 5 V,	$V_0 = 2.5 \text{ V or } 0.5 \text{ V}$		16			16		pF

<sup>†</sup> All typical values are at  $V_{CC} = 5 \text{ V}$ ,  $T_A = 25^{\circ}\text{C}$ .

# timing requirements over recommended ranges of supply voltage and operating free-air temperature (unless otherwise noted)

				$V_{CC} = 5 \text{ V},$ $T_A = 25^{\circ}\text{C}$		SN54BCT543		SN74BCT543	
			MIN	MAX	MIN	MAX	MIN	MAX	
t <sub>W</sub>	t <sub>W</sub> Pulse duration, LEAB or LEBA low		7		8		7		ns
t <sub>su</sub>	Setup time, data before LEAB or LEBA↑	High or low	4.5		5.5		4.5		ns
th	Hold time, data after LEAB or LEBA↑	High or low	1.5		1.5		1.5		ns

<sup>&</sup>lt;sup>‡</sup> For I/O ports, the parameters I<sub>IH</sub> and I<sub>IL</sub> include the off-state output current.

<sup>§</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed one second.

## switching characteristics (see Note 2)

PARAMETER	FROM TO (OUTPUT)		$V_{CC}$ = 5 V, $C_L$ = 50 pF, $R1$ = 500 $\Omega$ , $R2$ = 500 $\Omega$ , $T_A$ = 25°C			$V_{CC}$ = 4.5 V to 5.5 V, $C_L$ = 50 pF, R1 = 500 Ω, R2 = 500 Ω, $T_A$ = MIN to MAX $^\dagger$				UNIT
		,	′1	′BCT543			SN54BCT543		SN74BCT543	
			MIN	TYP	MAX	MIN	MAX	MIN	MAX	]
t <sub>PLH</sub>	A or B	B or A	2	5.7	7.5	2	9.9	2	8.8	
tPHL			2	6.3	8.2	2	9.7	2	9.6	ns
t <sub>PLH</sub>	<u>LE</u>	A or B	2	8.2	10.3	2	13.9	2	12.9	-l ns l
t <sub>PHL</sub>	LE		2	8.5	10.6	2	13.2	2	12.7	
<sup>t</sup> PZH	ŌĒ	A or B	1	6.8	8.6	1	11.4	1	10.7	ns
tpzL	OE	AOIB	1	8.7	10.8	1	12.8	1	12.3	115
t <sub>PHZ</sub>	ŌĒ	A or B	1	5.5	7.2	1	8.8	1	8.1	ns
tPLZ	OE	AOIB	1	4.7	6.4	1	8.1	1	7.2	115
<sup>t</sup> PZH	CE	A or B	1	7.6	9.8	1	12.8	1	12	ns
<sup>t</sup> PZL		AUID	1	9.5	11.6	1	13.8	1	13.5	115
<sup>t</sup> PHZ	CE	`F	1	5.8	7.5	1	9.3	1	8.5	ns
t <sub>PLZ</sub>	OL .	A or B	1	4.8	6.7	1	8.4	1	7.6	115

<sup>†</sup> For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions. NOTE 2: Load circuits and voltage waveforms are shown in Section 1.



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